



PATENT APPLICATION

THE UNITED STATES PATENT AND TRADEMARK OFFICE

In the Application of

Eiji NATORI

Group Art Unit: 2813

Application No.: 09/819,688

Examiner: D. Hogans

Filed: March 29, 2001

Docket No.: 109120

For: METHOD AND DEVICE FOR MANUFACTURING CERAMICS, SEMICONDUCTOR  
DEVICE AND PEIZOELECTRIC DEVICE

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the reference(s) listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the reference(s) be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

- ☒ 1. This Information Disclosure Statement is being filed more than three months after the U.S. filing date and after the mailing date of a Final Rejection, Notice of Allowance, or other action that closes prosecution (e.g., Quayle Action), but before payment of the Issue Fee. Attached is our Check No. 144802 in the amount of \$180.00 in payment of the fee under 37 CFR §1.17(p). Please credit or debit Deposit Account No. 15-0461 as needed to ensure consideration of the disclosed information. Two duplicate copies of this paper are attached.
- ☒ a. I hereby certify that each item of information contained in this Information Disclosure Statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this Information Disclosure Statement.  
37 CFR §1.97(e)(1).
- ☒ 2. Each item of information contained in this Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart application, and this communication was not received by any individual designated in §1.56(c) more than thirty days prior to the filing of this Information Disclosure Statement.

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- ☒ 3. The references were cited in a counterpart foreign application. An English language version of the foreign search report is attached for the Examiner's information.
- ☒ 4. English-language Abstract of the non-English language reference is attached hereto for FR 2 729 400 - A1.

Respectfully submitted,



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Date: August 1, 2003

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| Form PTO-1449<br>(REV. 8-83)  |  | US Dept. of Commerce<br>PATENT & TRADEMARK OFFICE  |            | ATTY DOCKET NO.<br>109120     |       | APPLICATION NO.<br>09/819,688 |  |
| <div style="text-align: center;">O I P E<br/>INFORMATION DISCLOSURE STATEMENT<br/>(Use several sheets if necessary)</div> <div style="text-align: center;">AUG 01 2003<br/>PATENT &amp; TRADEMARK OFFICE</div>                              |  |  |            | APPLICANT<br>Eiji NATORI      |       |                               |  |
|   |  |  |            | FILING DATE<br>March 29, 2001 |       | GROUP<br>2813                 |  |
| U.S. PATENT DOCUMENTS   |  |  |            |                               |       |                               |  |
| EXAMINER<br>INITIAL   |  | DOCUMENT NUMBER  | DATE       | NAME                          | CLASS | SUB<br>CLASS                  |  |
|   |  | 5,624,720  | 04-29-1997 | Osada et al.                  |       |                               |  |
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| FOREIGN PATENT DOCUMENTS  |  |  |            |                               |       |                               |  |
|   |  | DOCUMENT NUMBER  | DATE       | COUNTRY                       | CLASS | SUB<br>CLASS                  |  |
|   |  | EP 0 828 012 A1  | 03-11-1998 | Europe                        |       |                               |  |
|   |  | FR 2 729 400 - A1 w/abstract   | 07-19-1996 | France                        |       |                               |  |
|   |  | WO 93/16811  | 09-02-1993 | WIPO                          |       |                               |  |
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|   |  | WO 99/02756  | 01-21-1999 | WIPO                          |       |                               |  |
| OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)  |  |  |            |                               |       |                               |  |
|   |  | Jpn. J. Appl. Phys. Vol. 33 (1994) pp. 5135-5138 Part 1, No. 9B, Sept. 1994; Effects of O <sub>3</sub> on Growth and Electric Properties of Pb(Zr, Ti)O <sub>3</sub> Thin Films by Photoenhanced Metalorganic Chemical Vapor Deposition. |            |                               |       |                               |  |
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| EXAMINER  |  |  |            | DATE CONSIDERED               |       |                               |  |
| Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. |  |  |            |                               |       |                               |  |

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